



4/17/2012

**RELIABILITY MONITOR REPORT
FOR**

X3 0.6 μ m Silicon Gate CMOS (S6)

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX4786EXS+T

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 29455 QUANTITY: 152 FAILS: 0 FITS: 3.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: X3 0.6µm Silicon Gate CMOS (S6)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1115	MAX4786EXS+T	135C	1000 HRS	77	0	IKM1BQ002Q2
HIGH TEMP OP LIFE	1115	MAX4786EXS+T	135C	1000 HRS	75	0	IKM1BQ002Q3
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1115	MAX4786EXS+T	150C	1000 HRS	80	0	IKM1BQ002Q3
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1115	MAX4786EXS+T	-65C TO 150C	1000 CYS	77	0	IKM1BQ002Q2
Total:						0	

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